

SENSOFAR.[®]
METROLOGY



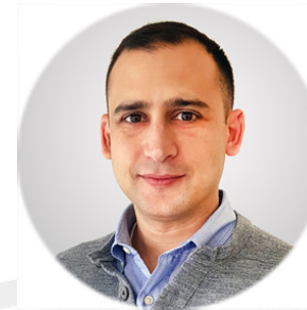
3D EDUCATIONAL DAY
3TH ANNUAL MEETING OF 3D2TWG
6TH NOVEMBER 2019
FBI ACADEMY





AGENDA

- ▣ The company
- ▣ S neox Forensics
- ▣ Measurement principles
- ▣ Firearms & toolmarks
- ▣ VCM
- ▣ Objective identification
- ▣ Critical dimensions
- ▣ Future



Adam Platteis
US Sales Manager



Cristina cadevall
PhD in Optics
VP Software

THE COMPANY

THE COMPANY

Headquarters & Sales Offices



Sensofar
METROLOGY

Barcelona (SPAIN)
1600 m² production
and R+D facilities



Sensofar ASIA
Shanghai (CH)
Taipei (TW)

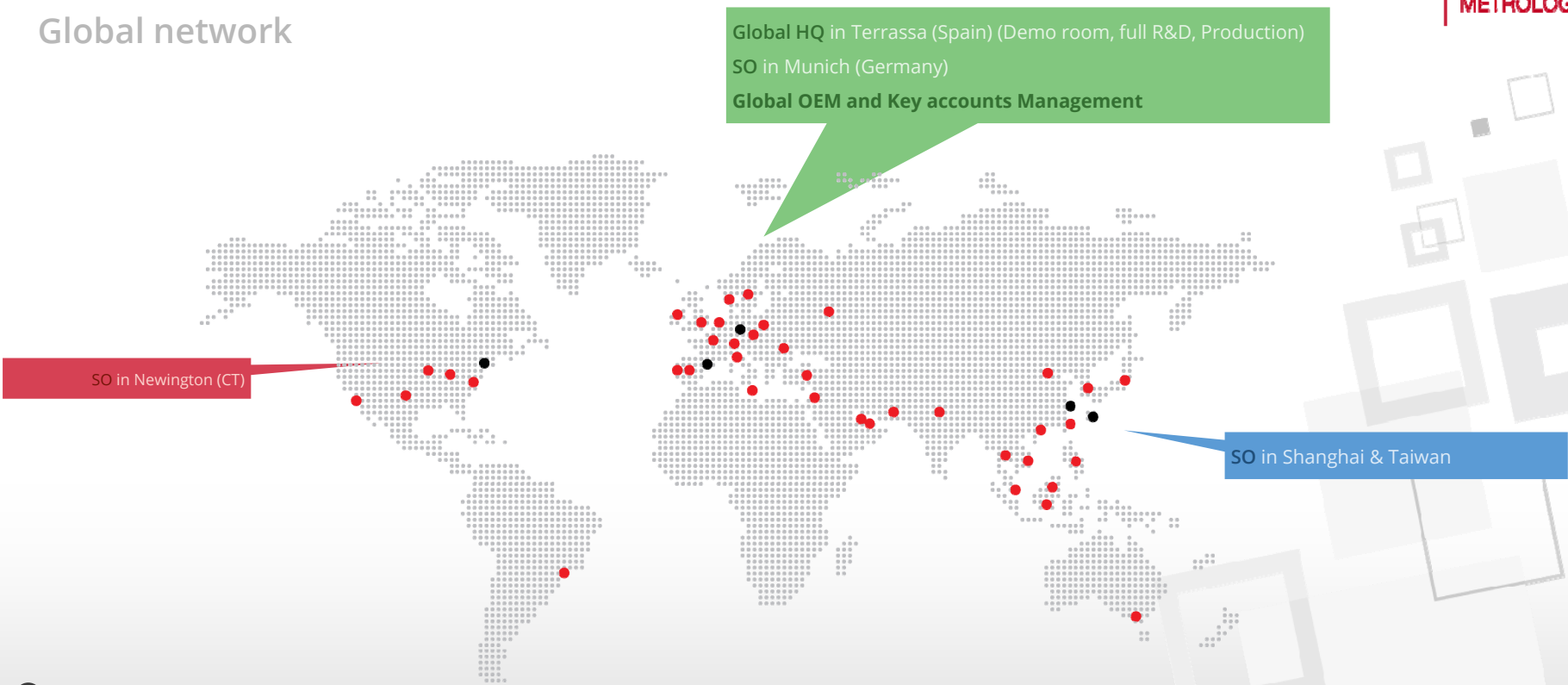
Sensofar GERMANY
Munich (GE)

Sensofar USA
Newington (US)

3DED 2019

THE COMPANY

Global network



Global HQ in Terrassa (Spain) (Demo room, full R&D, Production)
SO in Munich (Germany)
Global OEM and Key accounts Management

SO in Newington (CT)

SO in Shanghai & Taiwan

 HQ & Sales offices

 Distribution partners & Reps

THE COMPANY

Sensofar Team



THE COMPANY

Applications



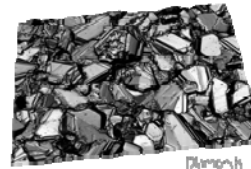
Automotive



Energy



LASER Processing



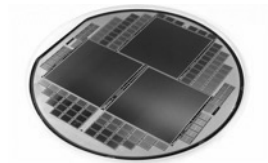
Diamonds



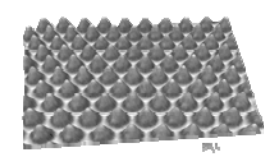
Leather



Microelectronics



Semiconductors



PSS



Micro manufacturing



Medical & Pharma



Tool Industry



Aerospace



Injection molding



Forensics

THE COMPANY

Customer references

SENSOFAR.
METROLOGY



+GF+

PTB

Leica
MICROSYSTEMS

Johnson & Johnson
MEDICAL DEVICES COMPANIES

EPFL
ÉCOLE POLYTECHNIQUE
FÉDÉRALE DE LAUSANNE



BOSCH

KIT
Karlsruhe Institute of Technology



RICHEMONT

IK4
TEKNIKER
Research Alliance

Stanford
University

UNIVERSITÀ
DEGLI STUDI
DI PADOVA

景碩科技



UNIVERSITY OF
ARKANSAS

pacea

SCANIA

IOWA STATE
UNIVERSITY

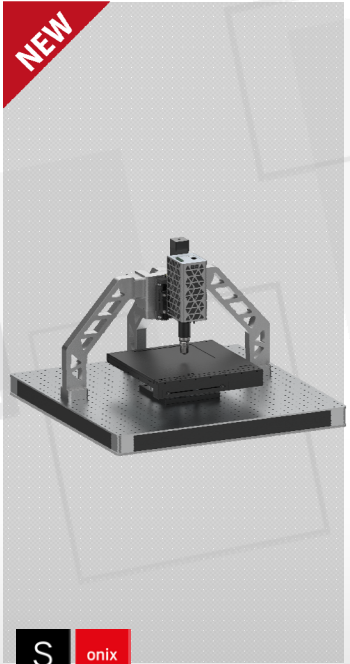
NIST

3DED 2019

THE COMPANY

Systems & Sensors

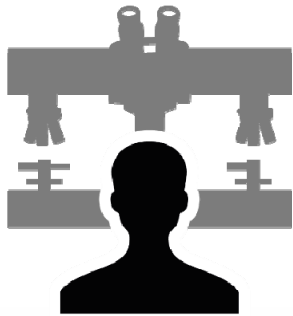
SENSOFAR.
METROLOGY



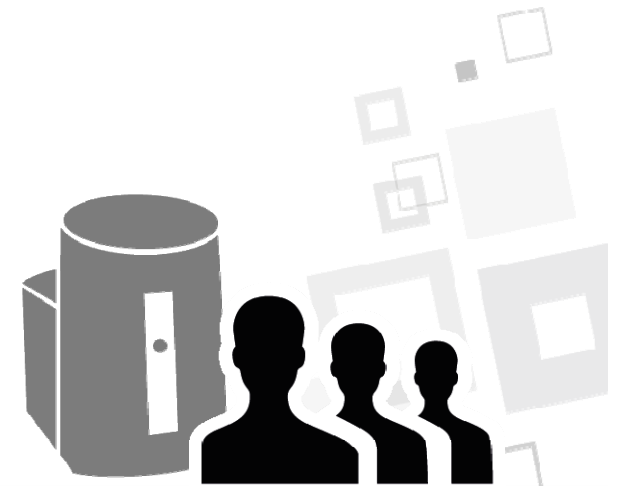
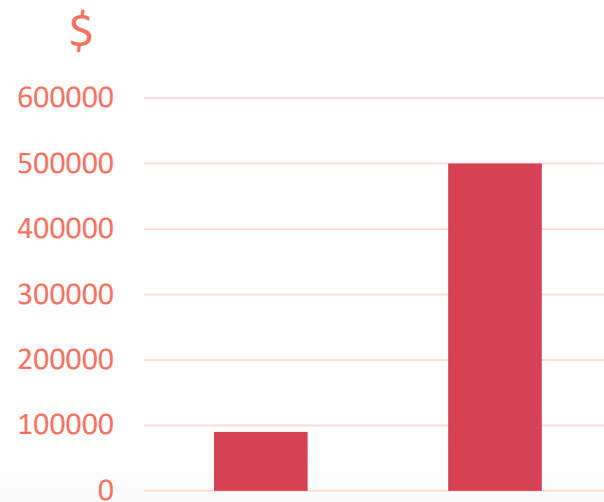
3DED 2019

S NEOX FORENSICS

S NEOX FORENSICS

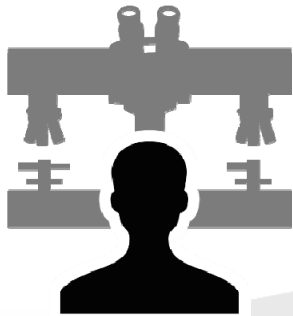


Comparison
microscope

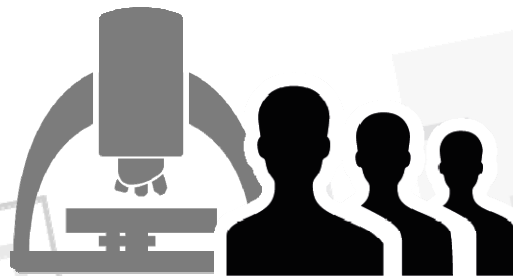


Automatic Ballistic
Identification Systems
(ABIS)

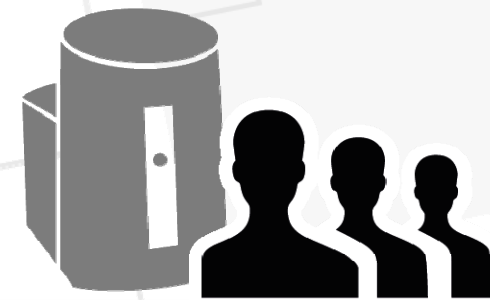
S NEOX FORENSICS



Comparison
microscope

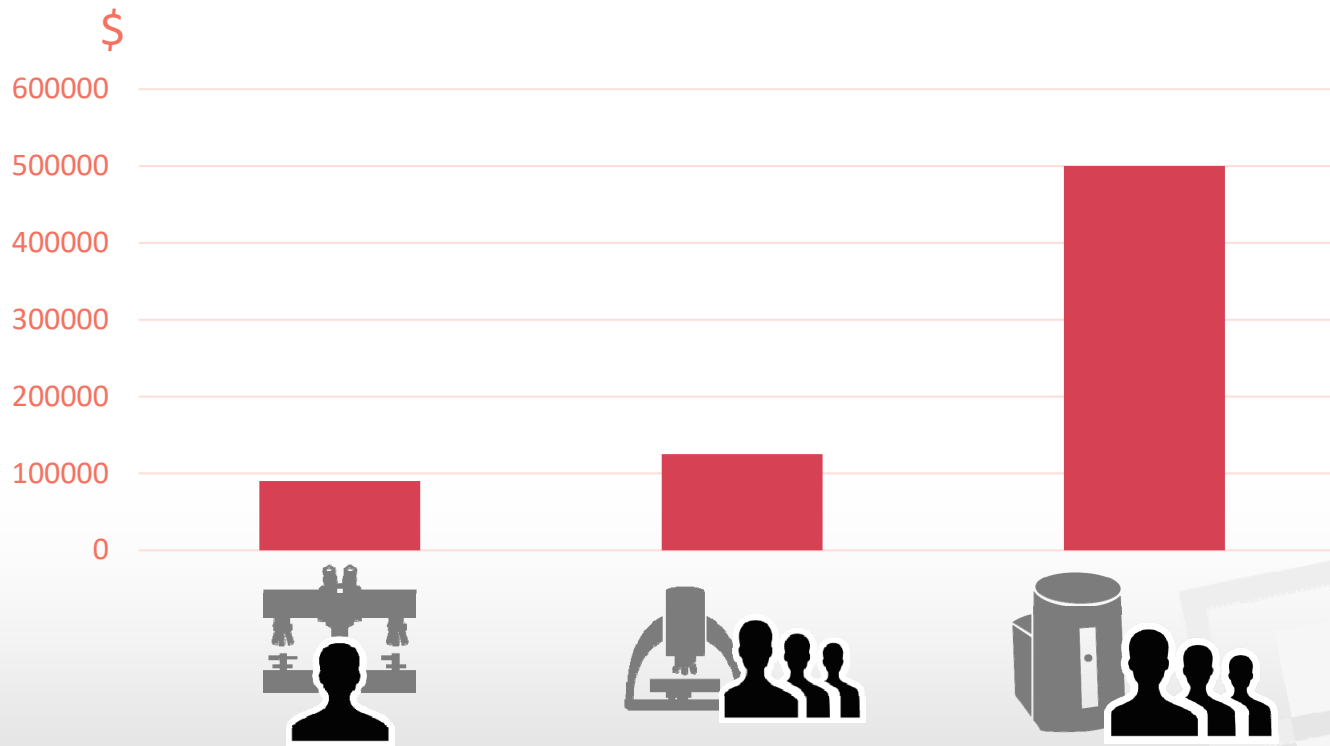


3D optical profiler



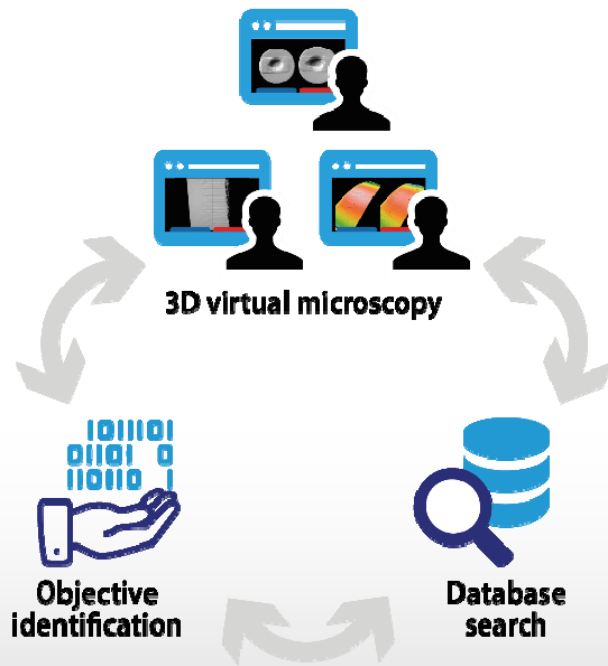
Automatic Ballistic
Identification Systems
(ABIS)

S NEOX FORENSICS



S NEOX FORENSICS

SENSOFAR.
METROLOGY

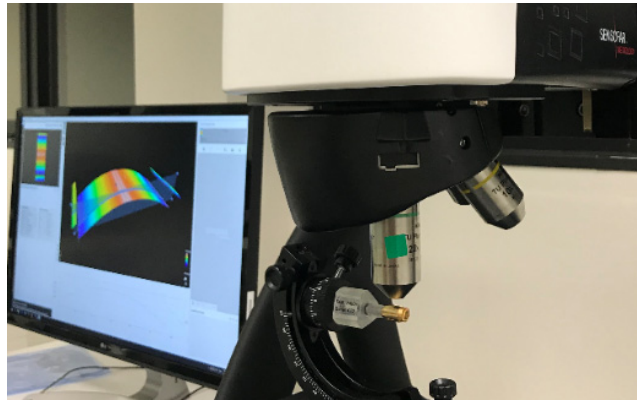


S neox
Forensics

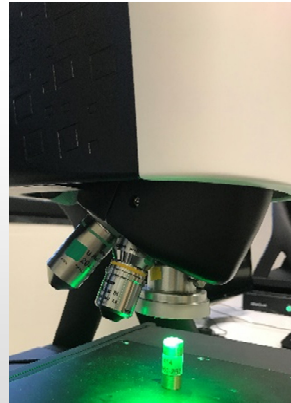
3DED 2019

S NEOX FORENSICS

Hardware options



Manual holder options



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METROLOGY



3DED 2019

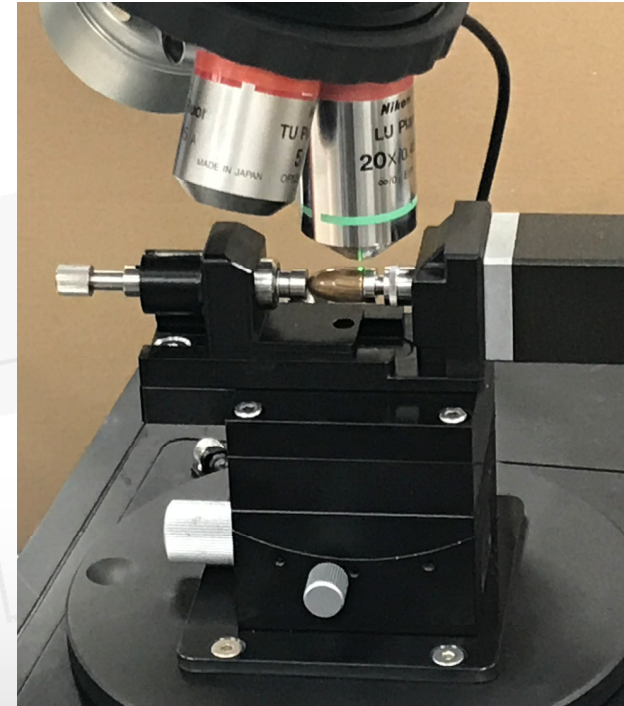
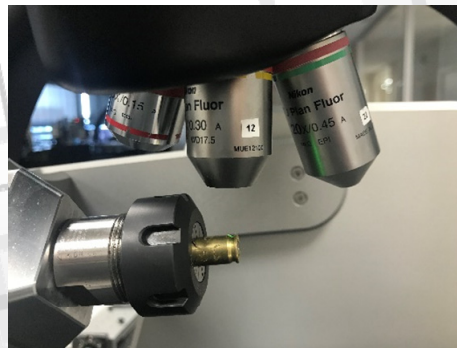
S NEOX FORENSICS

Hardware options

SENSOFAR.
METROLOGY



Five axis option



Four axis option

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S NEOX FORENSICS

Hardware options

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METROLOGY











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S NEOX FORENSICS

Software

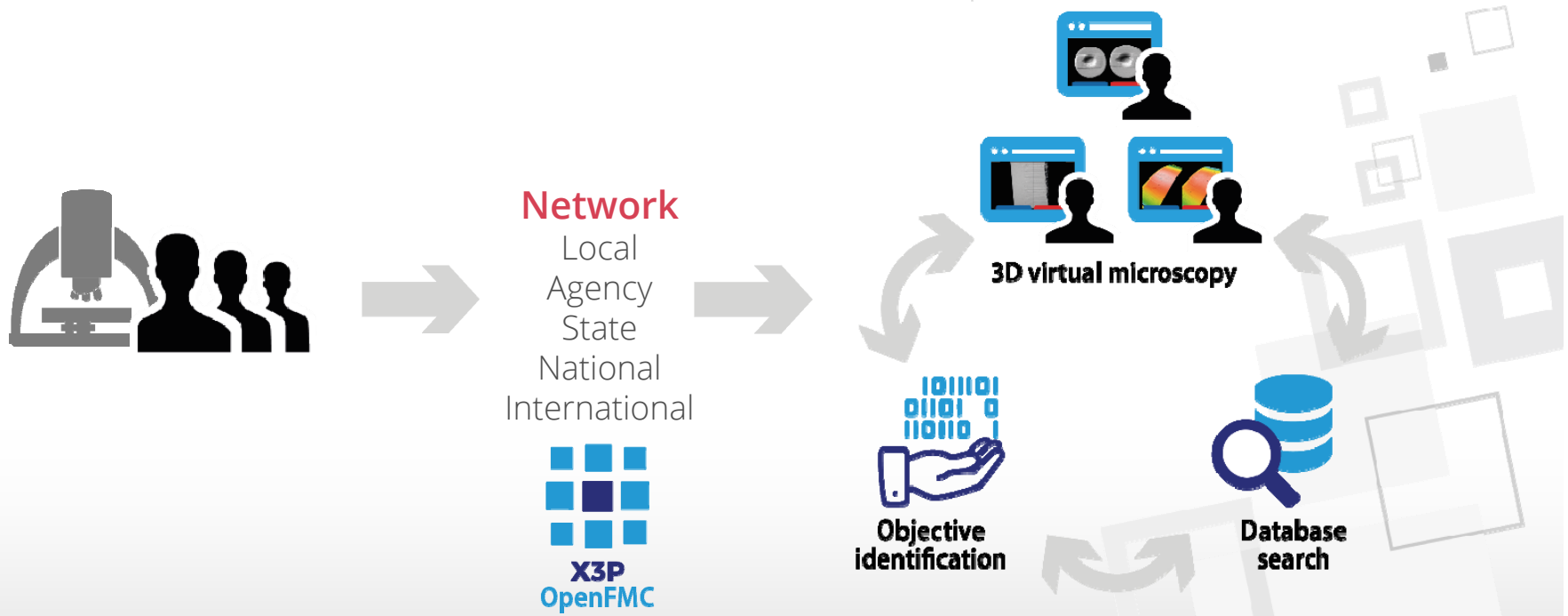
SENSOFAR.
METROLOGY

ACQUISITION	ANALYSIS	AUTOMATION & ANALYSIS	SDK
			
SensoSCAN 7	SensoCOMP	SensoMATCH option	SDK option
			
SensoFIVE 7 option	SensoVIEW	SensoPRO 3 option	
			
	SensoMAP option		

S NEOX FORENSICS

Open system

SENSOFAR.
METROLOGY



S NEOX FORENSICS

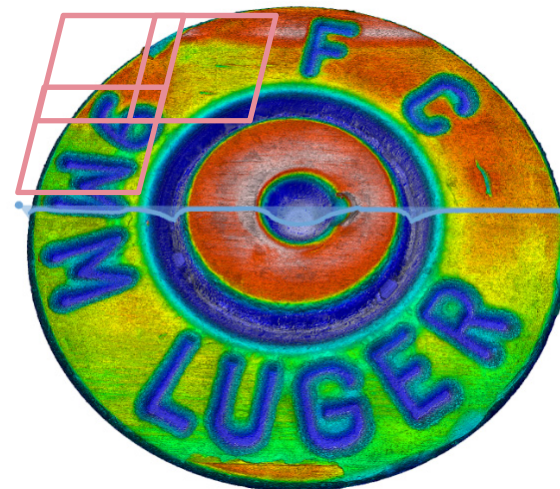
Automation

SENSOFAR.
METROLOGY

Automated procedures
module (APM)



Extended measurement
module (EMM)



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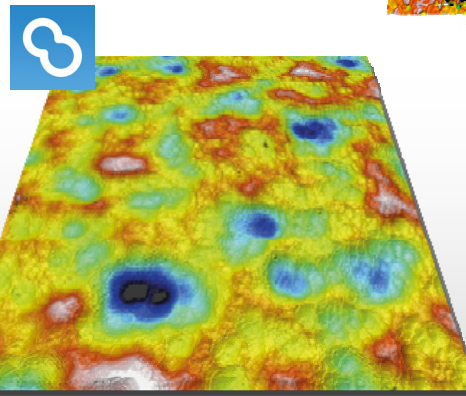
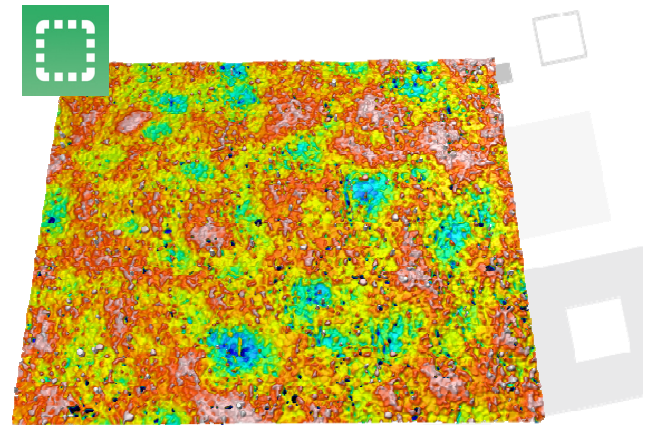
MEASUREMENT PRINCIPLES

MEASUREMENT PRINCIPLES

Performance comparison

	FOCUS VARIATION	CONFOCAL	INTERFEROMETRY
Rough samples	★★★	★★★★	★
Smooth samples		★★	★★★★
Micro-scale features	★★	★★★★	★★★★
Nano-scale features		★★	★★★★
High local slopes	★★★	★★	★
Thickness		★★★★	★★★★

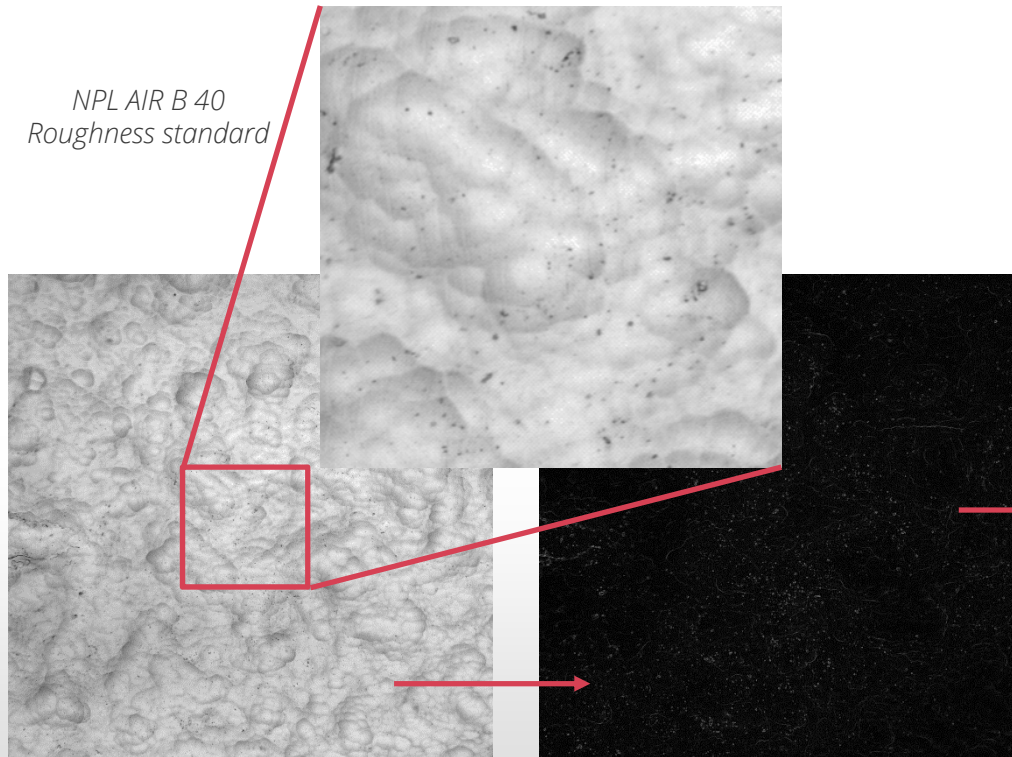
NPL AIR B 40
Roughness standard



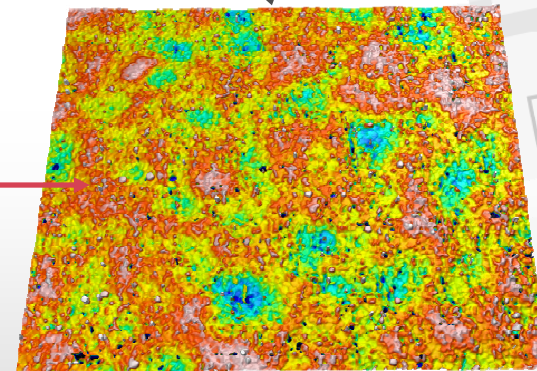
MEASUREMENT PRINCIPLES

Focus Variation

*NPL AIR B 40
Roughness standard*



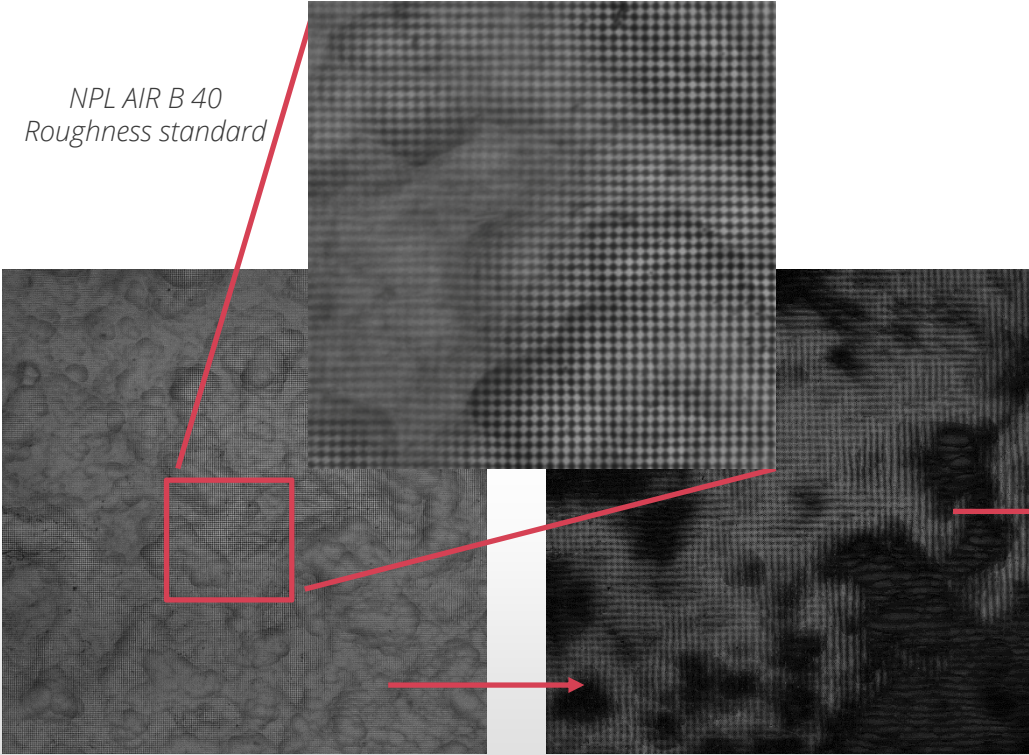
Focus Variation
on smooth
surface



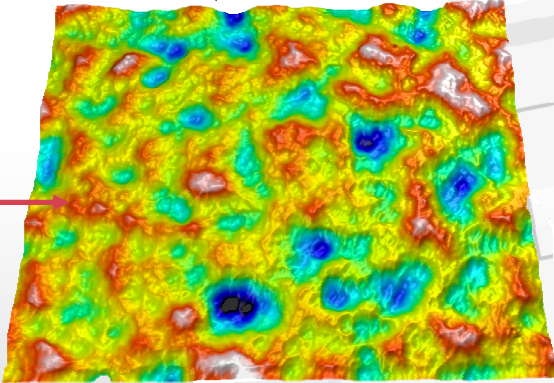
MEASUREMENT PRINCIPLES

Active Illumination Focus Variation

*NPL AIR B 40
Roughness standard*



Active Illumination
Focus Variation on
smooth surface

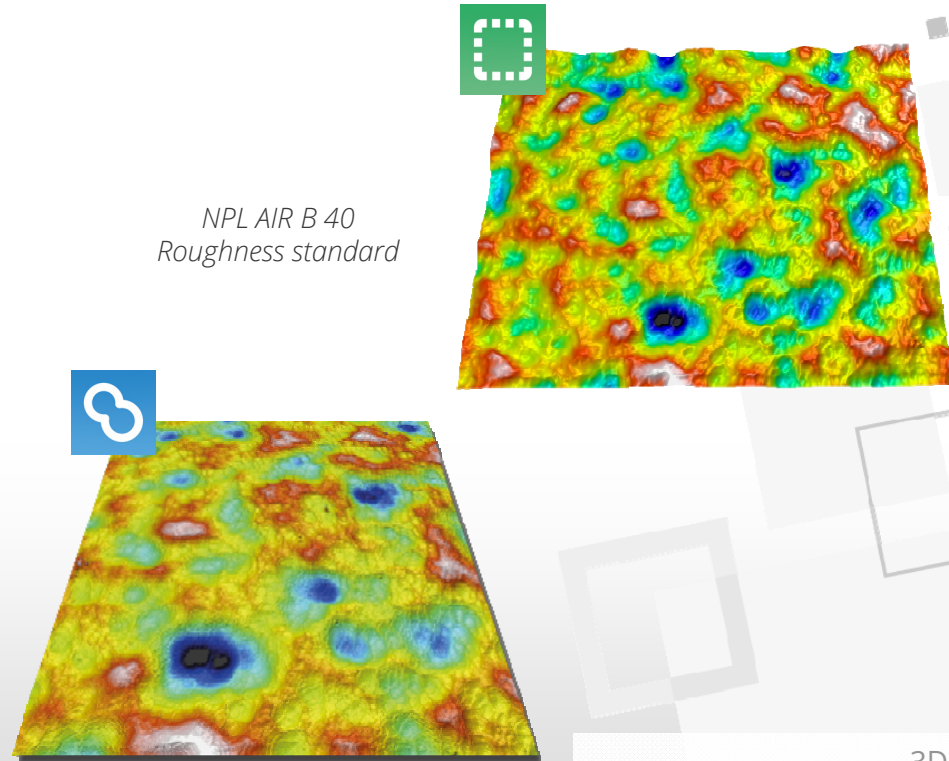


MEASUREMENT PRINCIPLES

Performance comparison

	Ai FOCUS VARIATION	CONFOCAL	INTERFEROMETRY
Rough samples	★ ★ ★	★ ★ ★	★
Smooth samples	★	★ ★	★ ★ ★ ★
Micro-scale features	★ ★	★ ★ ★	★ ★ ★ ★
Nano-scale features		★ ★	★ ★ ★ ★
High local slopes	★ ★ ★	★ ★	★
Thickness		★ ★ ★	★ ★ ★ ★

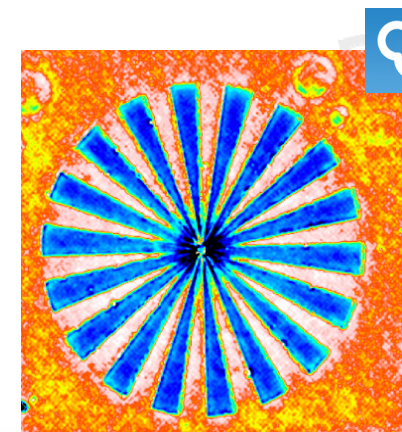
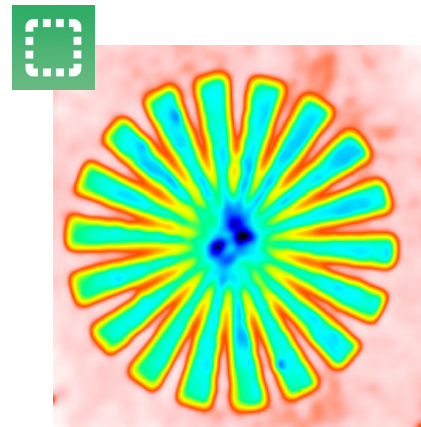
NPL AIR B 40
Roughness standard



MEASUREMENT PRINCIPLES

Performance comparison

	AI FOCUS VARIATION	CONFOCAL	INTERFEROMETRY
Rough samples	☆☆☆	☆☆☆	☆
Smooth samples	☆	☆☆	☆☆☆☆
Micro-scale features	☆☆	☆☆☆	☆☆☆☆
Nano-scale features		☆☆	☆☆☆☆
High local slopes	☆☆☆	☆☆	☆
Thickness		☆☆☆	☆☆☆☆



Siemens Star from NPL Bento Box, model ASP-02 P18
20X 0.45 NA 0.46 μm center wavelength

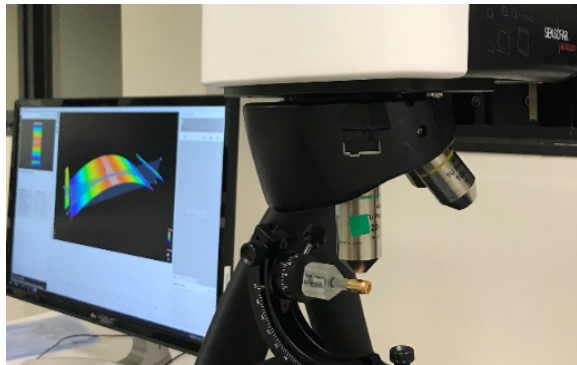
[Active illumination focus variation](#)

[Carlos Bermudez](#), [Pol Martinez](#), [Cristina Cadevall](#), [Roger Artigas](#)

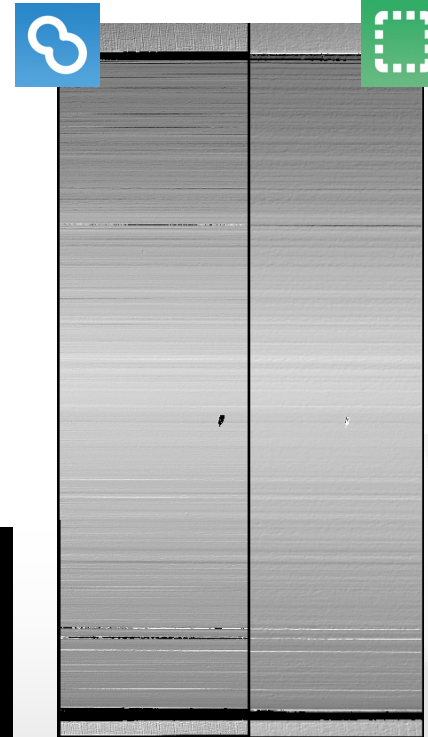
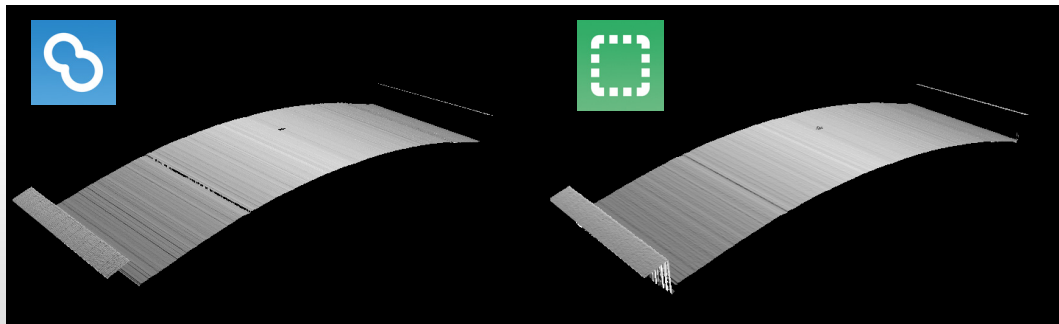
Proc. SPIE. 11056, Optical Measurement Systems for Industrial Inspection XI

MEASUREMENT PRINCIPLES

Bullets

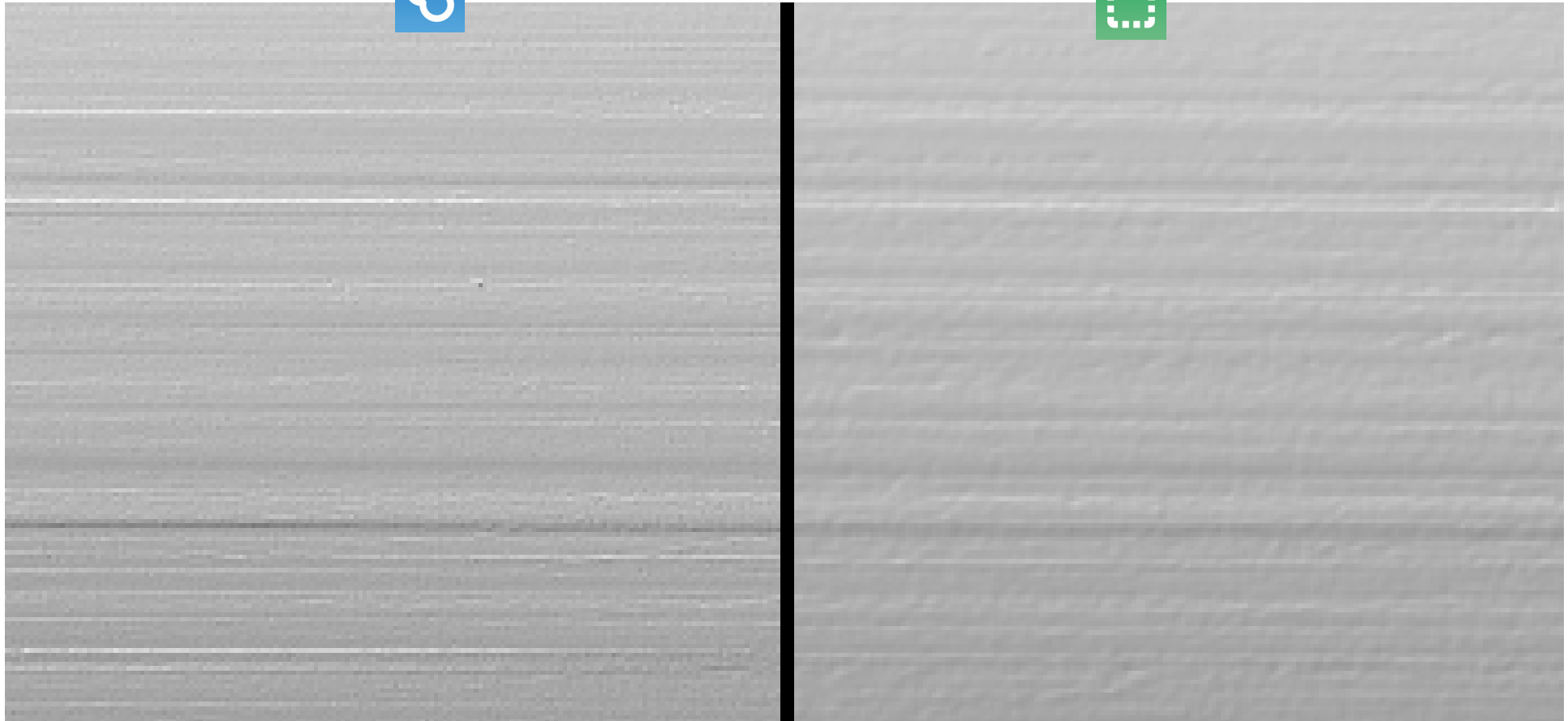


NIST Standard Reference Material 2460a Land 1



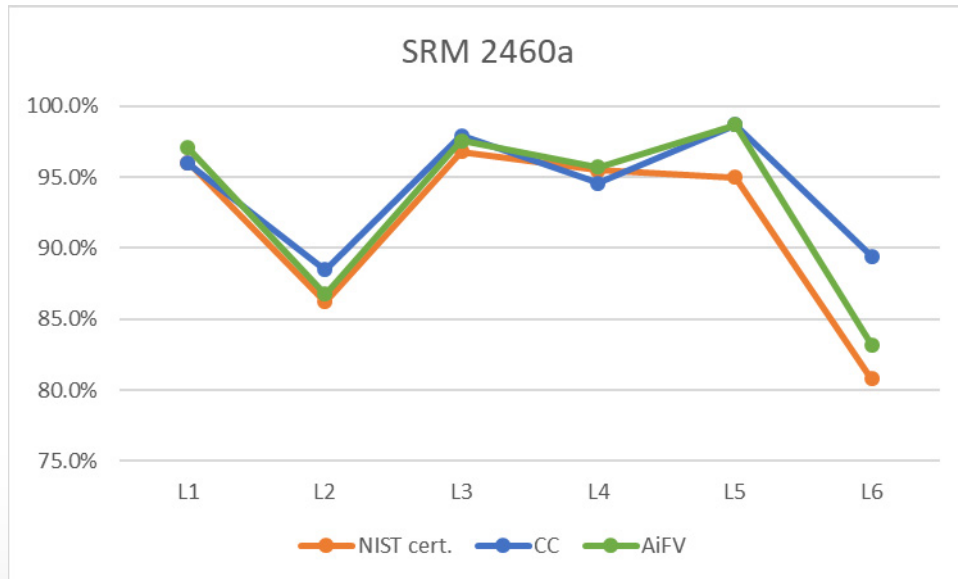
MEASUREMENT PRINCIPLES

Bullets



MEASUREMENT PRINCIPLES

Bullets



NIST Standard Reference Material 2460a lands

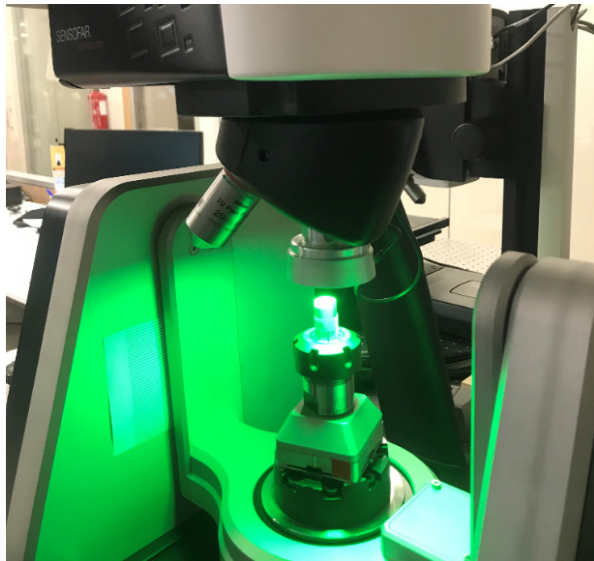
20X EPI objective

0.45 NA, pixel size 0.69 μm

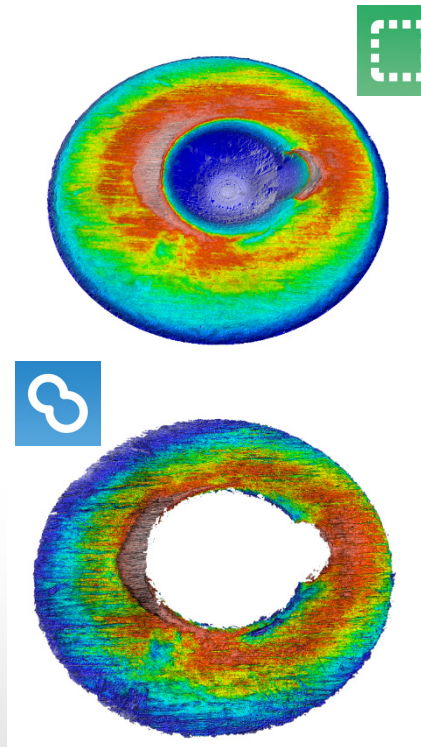


MEASUREMENT PRINCIPLES

Cartridge cases



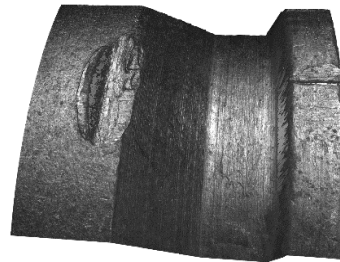
NIST Standard Reference Material 2461



FIREARMS & TOOLMARKS

FIREARMS & TOOLMARKS

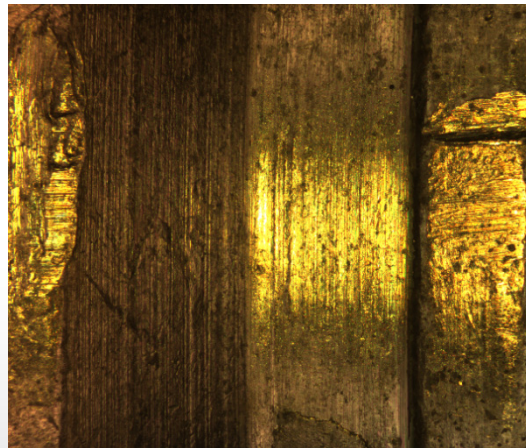
2D images



Extractor mark surface WVU CA
10X EPI
3D + Stack image



5X EPI color image



5X EPI all-in-focus color



5X EPI all-in-focus reflectivity

FIREARMS & TOOLMARKS

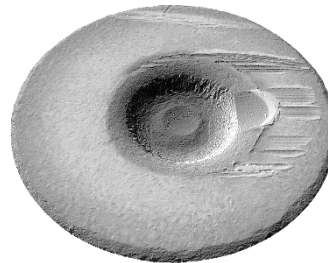
3D topographies



Cartridges provided by Eric Law
West Virginia University



Top cartridge case surface WVU CA
5X EPI / 3D + color image



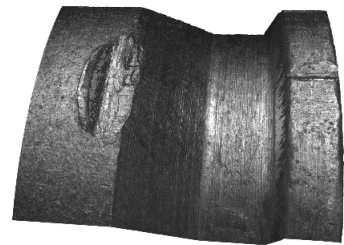
Breech face surface WVU CB
10X EPI / 3D + directional rendering



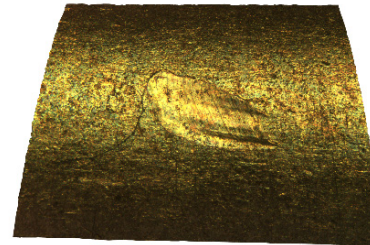
Ejector mark SRM2461
20X EPI / 3D + stack image



25 s
to
8 min 30 s



Extractor mark surface WVU CA
10X EPI / 3D + stack image



Chamber mark surface WVU CA
5X EPI / 3D + color image

FIREARMS & TOOLMARKS

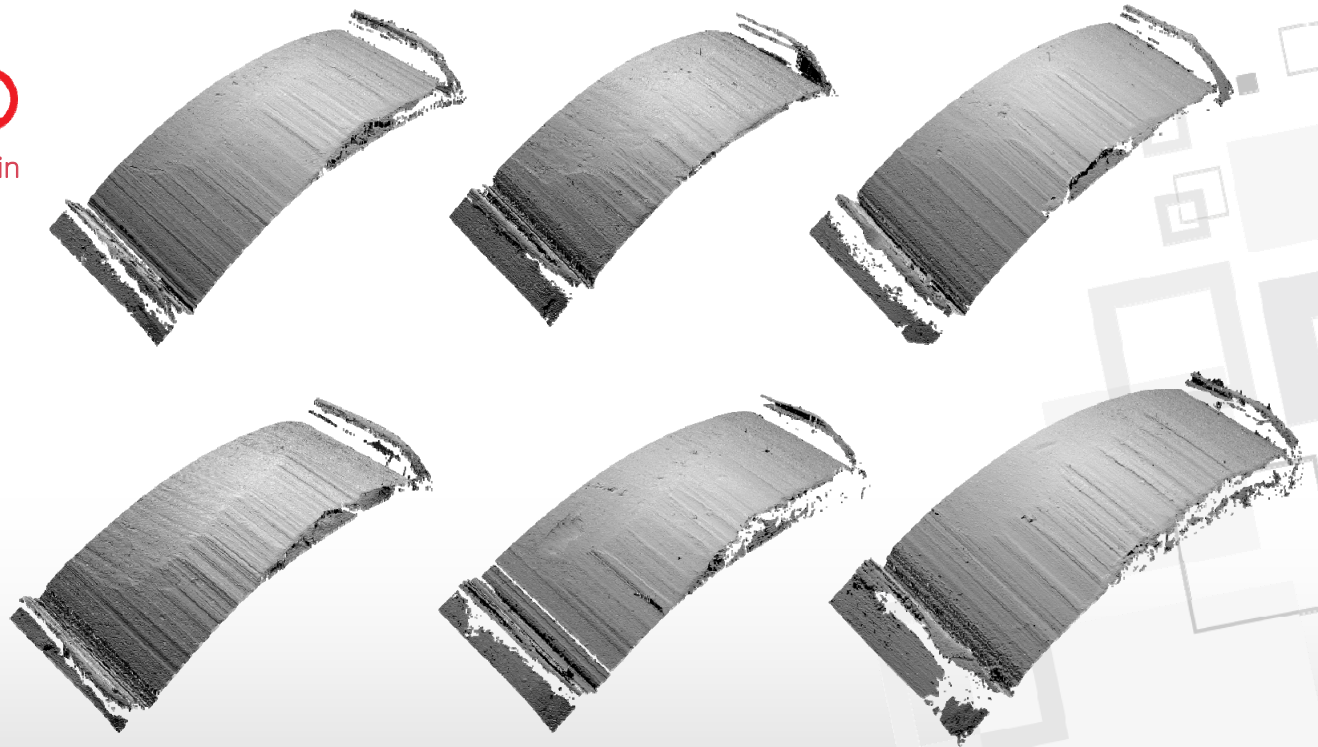
LEA 3D topographies



Bullets provided by Tylor Klep
Phoenix Police Department



6 min



Land surfaces
20X EPI / 3D + directional rendering

3DED 2019

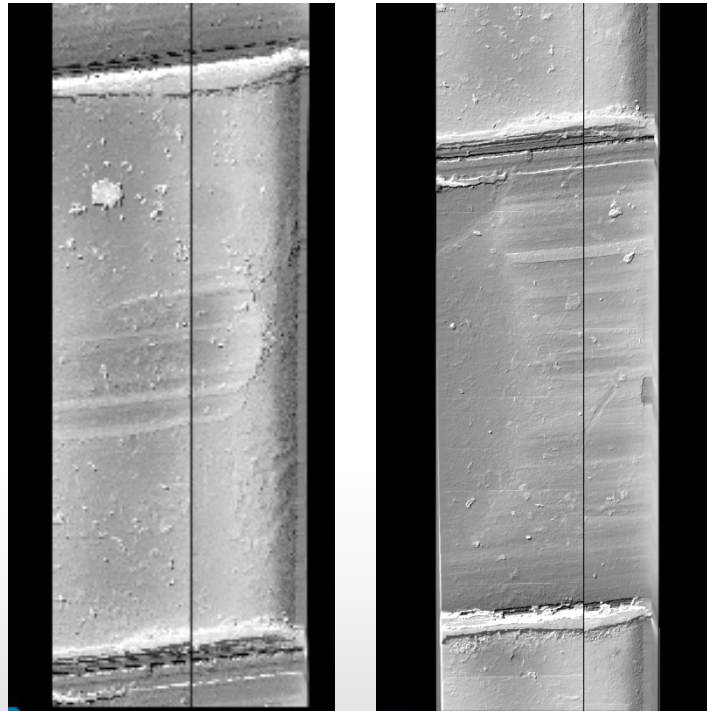
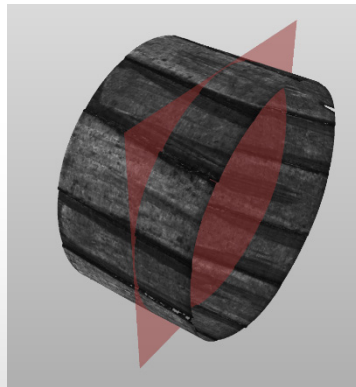
FIREARMS & TOOLMARKS

Full 3D and unrolled topographies



15 min

*Bullets provided by Tylor Klep
Phoenix Police Department*



Comparison of groove and land surfaces
20X EPI / Contour + directional rend

FIREARMS & TOOLMARKS

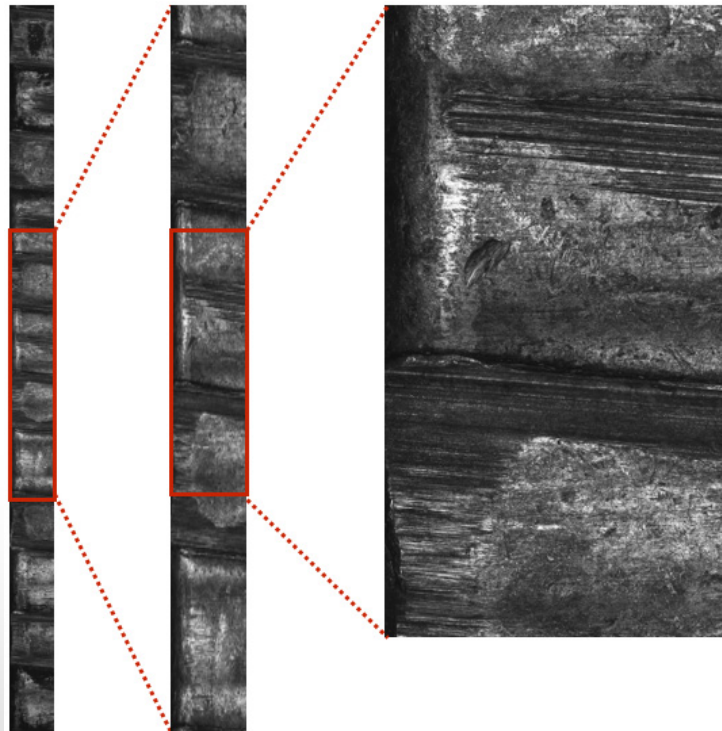
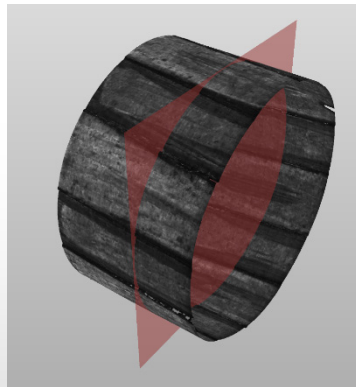
Full 3D and unrolled reflectivity images



Bullets provided by Tylor Klep
Phoenix Police Department



15 min



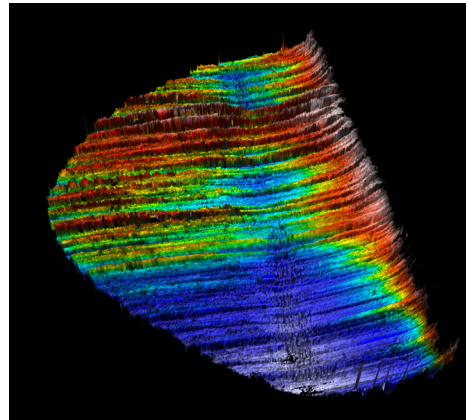
Groove and land details
20X EPI / Reflectivity image

FIREARMS & TOOLMARKS

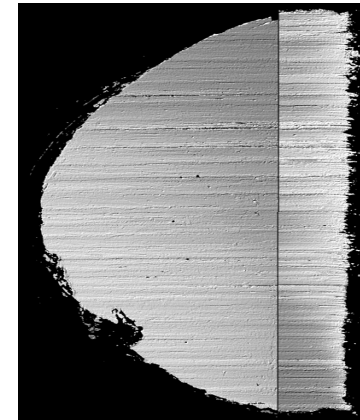
3D topographies



1 min



Cable surface
20X EPI / 3D + false color rendering



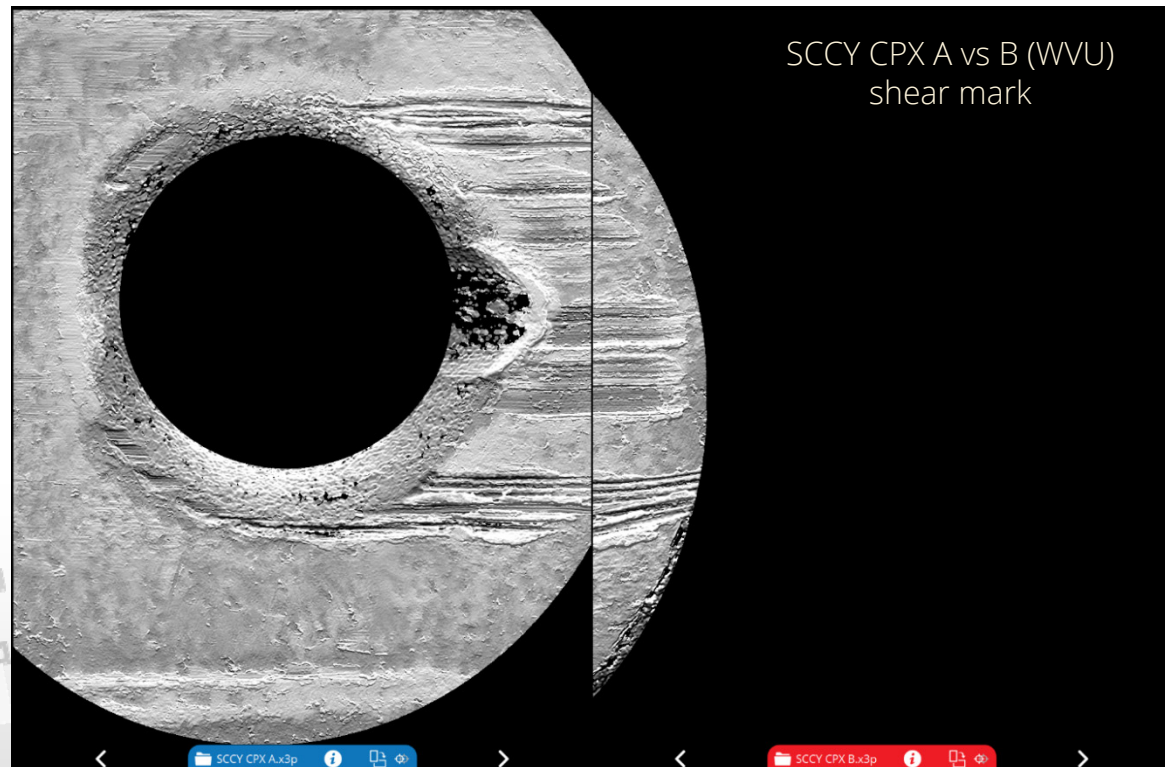
Cable surfaces comparison
20X EPI / Contour + directional rendering

*Cables provided by Jean-Alexandre Patteet
École des Sciences criminelles (UNIL)*

VCM

VCM

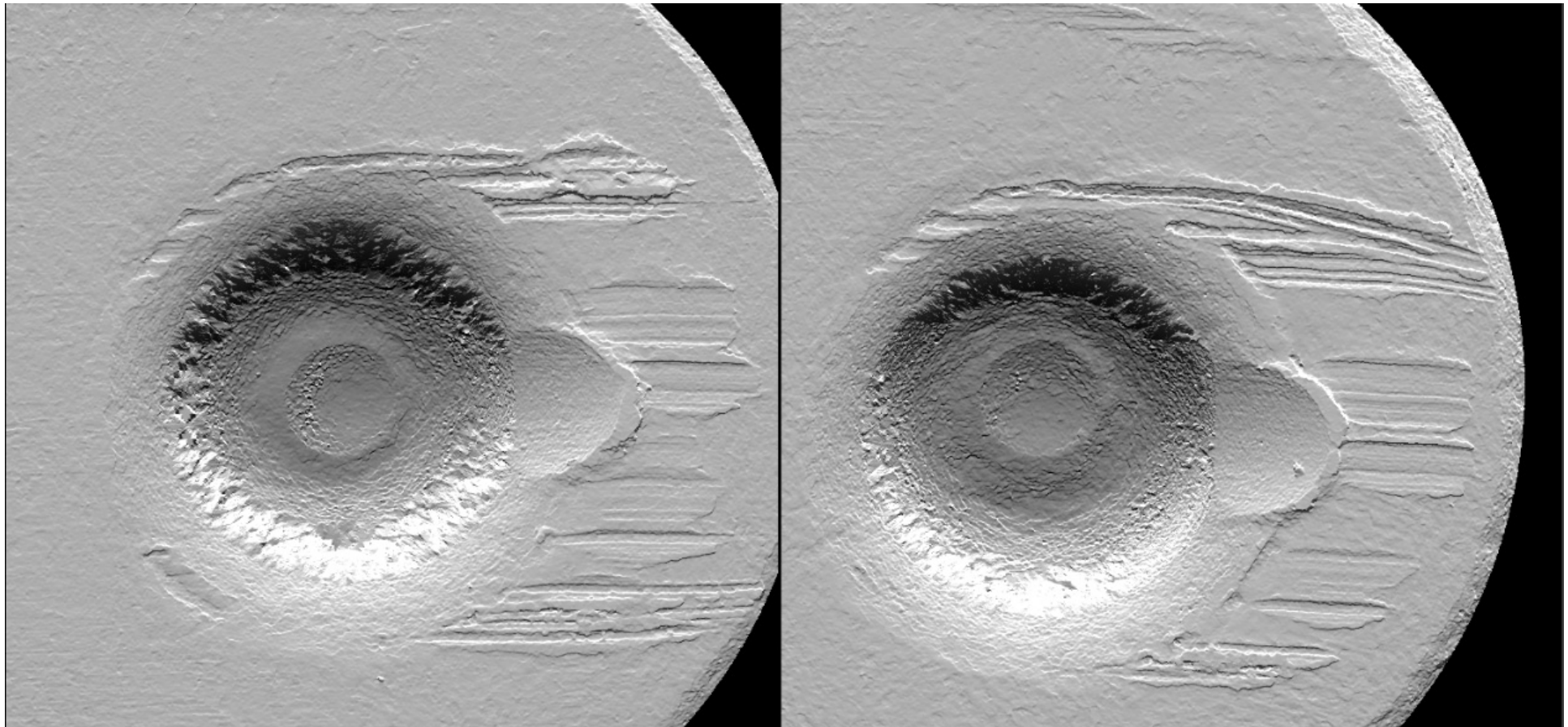
Analysis capabilities



VCM

Analysis capabilities

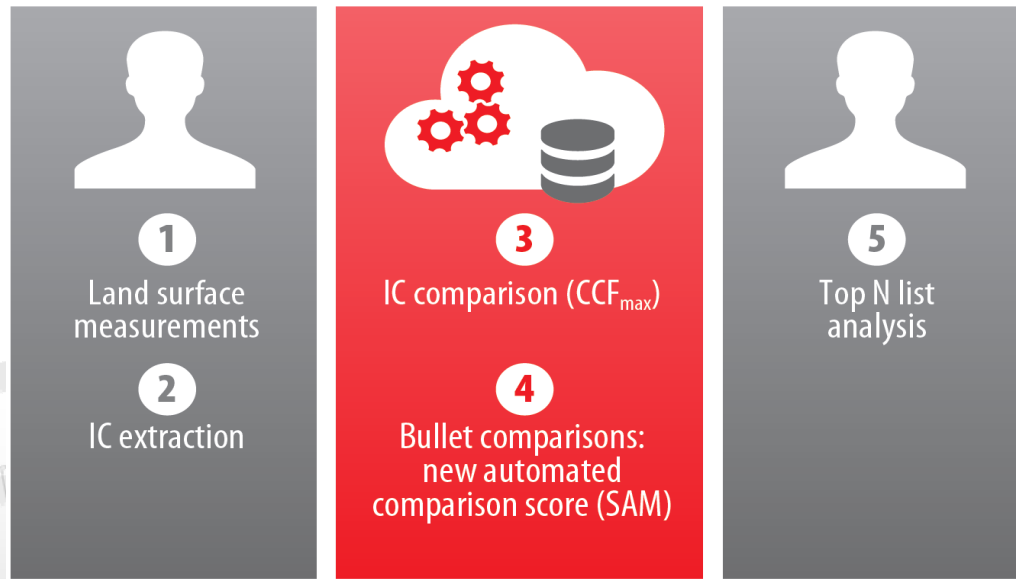
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OBJECTIVE IDENTIFICATION

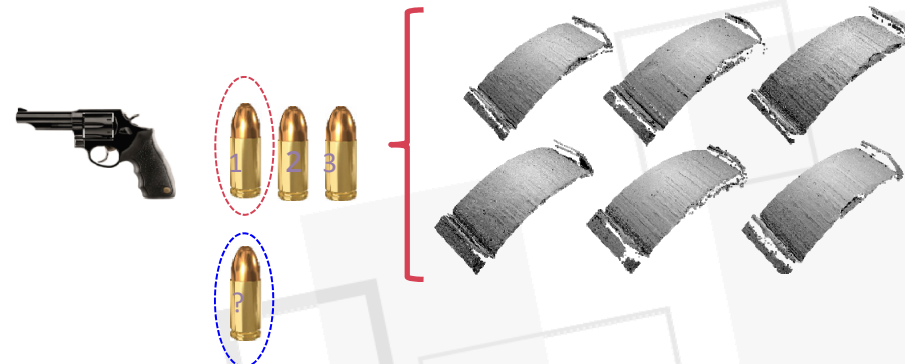
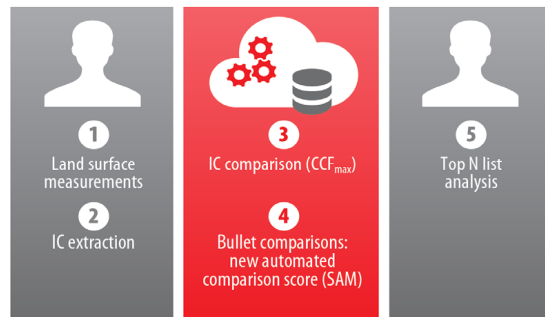
OBJECTIVE IDENTIFICATION

Bullets



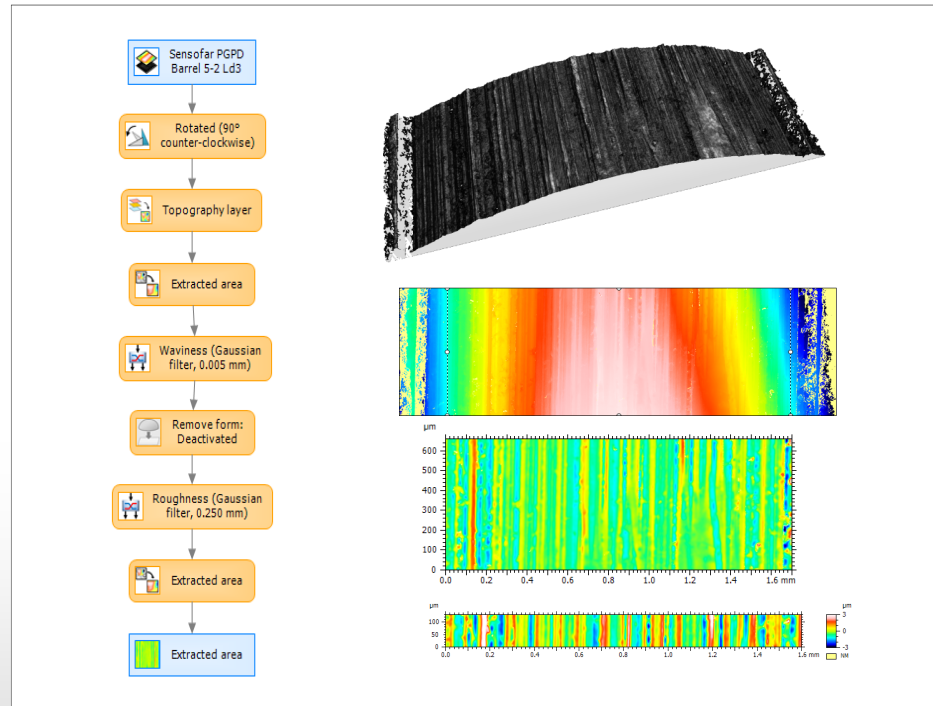
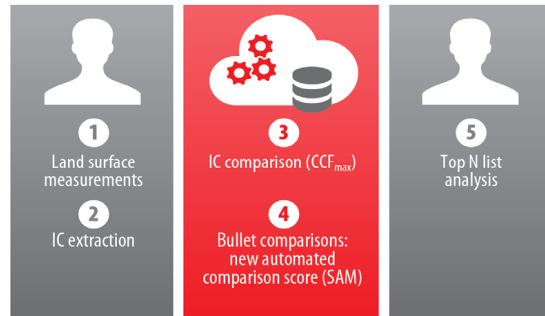
OBJECTIVE IDENTIFICATION

Bullets



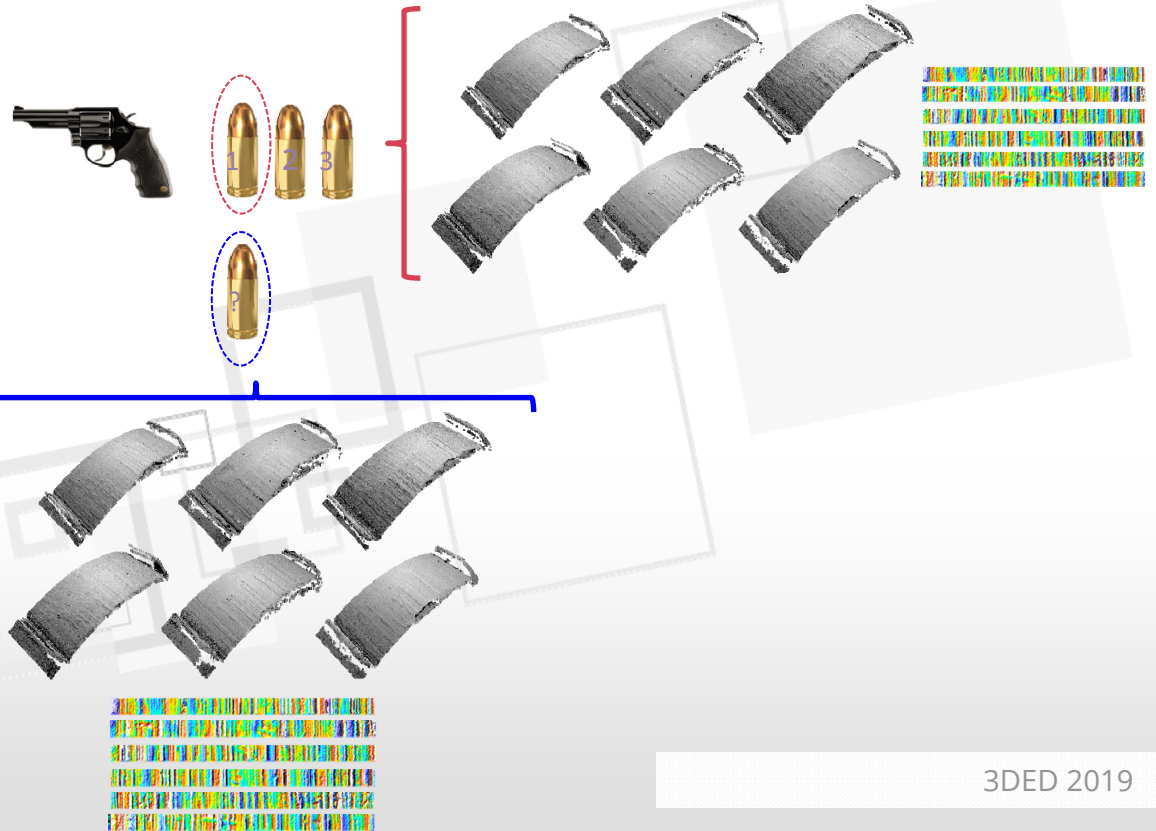
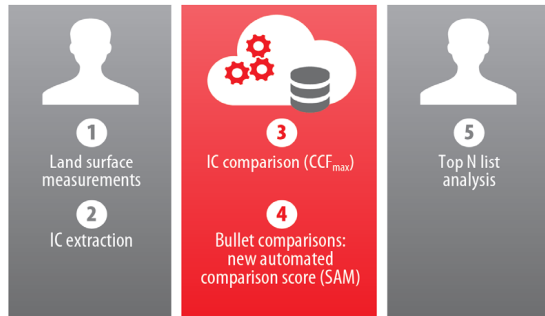
OBJECTIVE IDENTIFICATION

Bullets



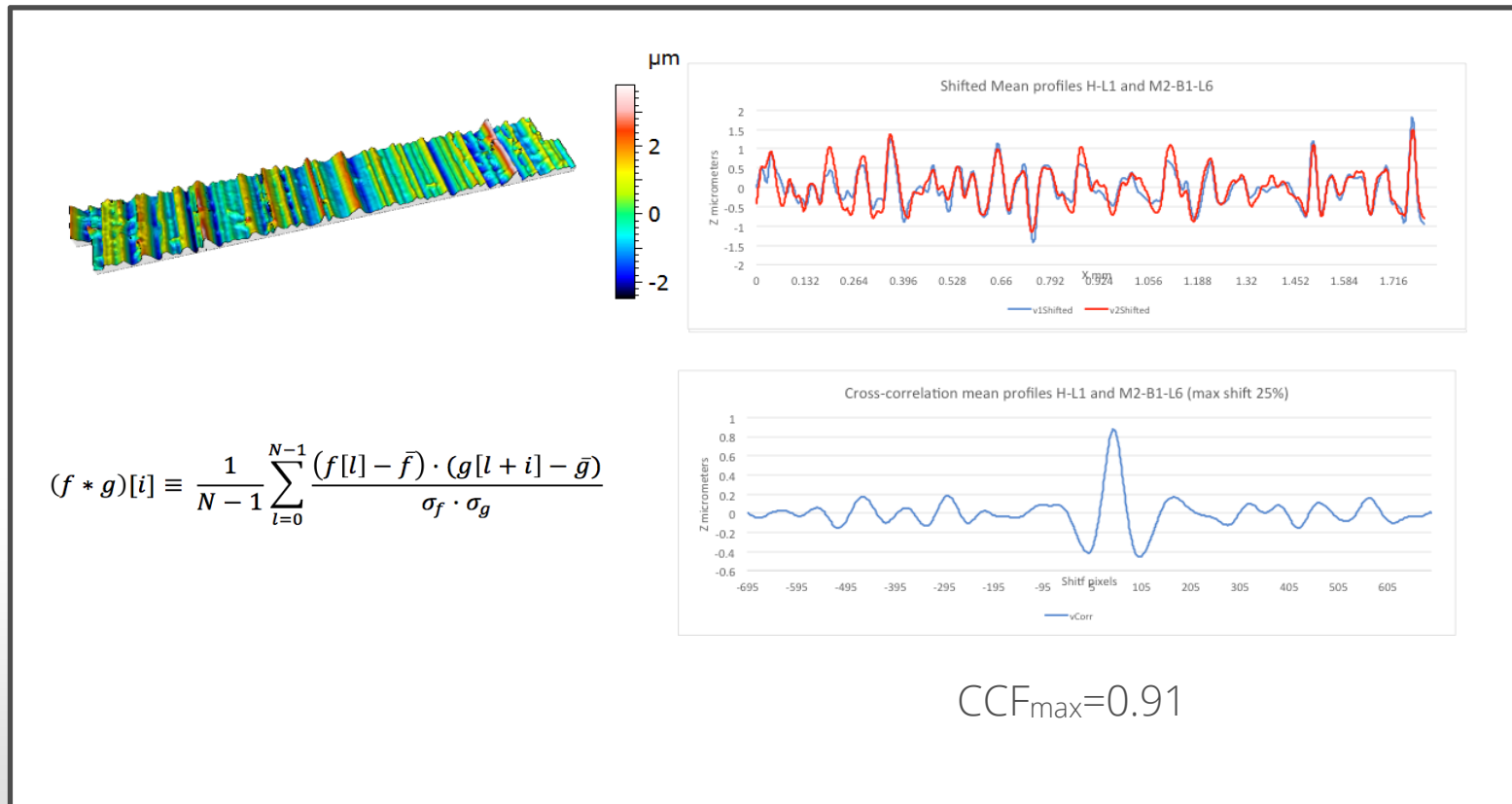
OBJECTIVE IDENTIFICATION

Bullets




OBJECTIVE IDENTIFICATION

Bullets




OBJECTIVE IDENTIFICATION

Bullets




1
Land surface measurements

2
IC extraction

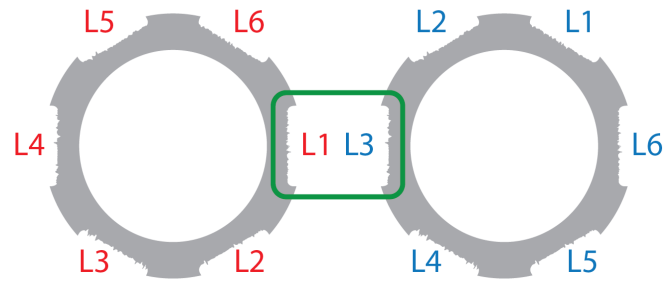


3
IC comparison (CCF_{max})

4
Bullet comparisons: new automated comparison score (SAM)



5
Top N list analysis



IC	L1	L2	L3	L4	L5	L6	Seq. Av
L1	0.28	0.31	0.88	0.27	0.28	0.36	0.30
L2	0.37	0.28	0.27	0.88	0.35	0.22	0.28
L3	0.24	0.28	0.24	0.33	0.89	0.27	0.77 SAM
L4	0.33	0.23	0.35	0.41	0.24	0.27	0.29
L5	0.87	0.24	0.27	0.31	0.26	0.29	0.25
L6	0.22	0.83	0.29	0.25	0.30	0.34	0.33

OBJECTIVE IDENTIFICATION

Bullets

1

Land surface measurements

2

IC extraction

3

IC comparison (CCF_{max})

4

Bullet comparisons:
new automated comparison score (SAM)

5

Top N list analysis

SensoMATCH results

SAM	B	C	D	E	F	H	J	L	M	Q	S	U	X	Y	Z
1 b1	0.33	0.77	0.32	0.32	0.77	0.32	0.31	0.28	0.30	0.30	0.31	0.31	0.30	0.32	0.34
1 b2	0.28	0.73	0.31	0.31	0.70	0.32	0.31	0.29	0.32	0.33	0.31	0.31	0.32	0.32	0.32
2 b1	0.29	0.33	0.30	0.31	0.31	0.81	0.29	0.30	0.30	0.31	0.29	0.32	0.28	0.32	0.29
2 b2	0.29	0.33	0.31	0.31	0.31	0.81	0.30	0.29	0.29	0.32	0.30	0.31	0.31	0.31	0.30
3 b1	0.28	0.30	0.32	0.30	0.32	0.28	0.33	0.28	0.29	0.30	0.61	0.29	0.64	0.30	0.31
3 b2	0.29	0.29	0.31	0.31	0.30	0.29	0.31	0.30	0.29	0.29	0.61	0.30	0.78	0.32	0.30
4 b1	0.67	0.31	0.33	0.33	0.31	0.31	0.32	0.29	0.30	0.32	0.32	0.33	0.30	0.35	0.33
4 b2	0.61	0.32	0.33	0.35	0.31	0.29	0.31	0.32	0.32	0.32	0.32	0.35	0.31	0.34	0.34
5 b1	0.30	0.34	0.88	0.37	0.34	0.29	0.33	0.30	0.35	0.33	0.32	0.31	0.29	0.34	0.85
5 b2	0.30	0.36	0.88	0.39	0.35	0.31	0.33	0.32	0.36	0.35	0.34	0.32	0.32	0.35	0.84
6 b1	0.27	0.31	0.32	0.78	0.32	0.30	0.27	0.28	0.62	0.28	0.28	0.28	0.28	0.74	0.32
6 b2	0.29	0.31	0.34	0.74	0.32	0.28	0.30	0.28	0.72	0.32	0.31	0.29	0.31	0.68	0.31
7 b1	0.33	0.32	0.33	0.32	0.30	0.32	0.85	0.30	0.29	0.31	0.36	0.30	0.31	0.32	0.33
7 b2	0.32	0.33	0.31	0.33	0.31	0.29	0.82	0.29	0.29	0.30	0.34	0.30	0.30	0.33	0.33
8 b1	0.31	0.32	0.31	0.31	0.29	0.33	0.29	0.78	0.30	0.29	0.32	0.32	0.30	0.32	0.28
8 b2	0.31	0.29	0.33	0.32	0.28	0.31	0.28	0.79	0.31	0.30	0.32	0.32	0.28	0.31	0.28
9 b1	0.30	0.33	0.32	0.31	0.35	0.33	0.30	0.36	0.31	0.30	0.33	0.69	0.32	0.32	0.33
9 b2	0.29	0.32	0.32	0.31	0.31	0.31	0.32	0.33	0.32	0.29	0.32	0.71	0.32	0.32	0.31
10 b1	0.30	0.28	0.32	0.34	0.28	0.30	0.28	0.26	0.31	0.55	0.32	0.31	0.29	0.34	0.34
10 b2	0.31	0.32	0.34	0.36	0.32	0.31	0.31	0.31	0.30	0.60	0.34	0.32	0.32	0.35	0.32

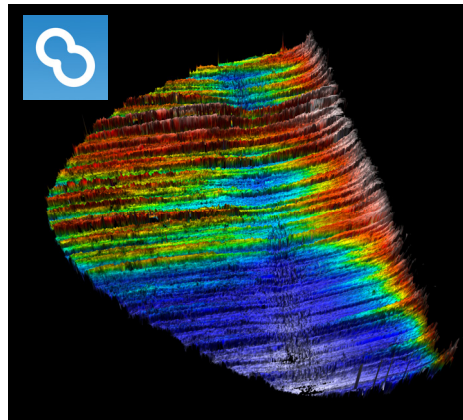
NIST results

B	C	D	E	F	H	J	L	M	Q	S	U	X	Y	Z
4	1	5	6	1	2	7	8	6	10	3	9	3	6	5

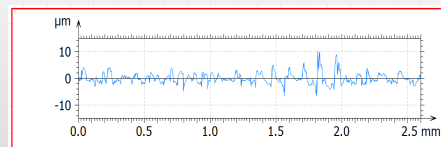
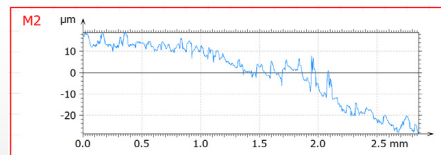
John Hamby test correctly solved
SAM threshold = 0.5

OBJECTIVE IDENTIFICATION

Cables



Cables provided by Jean-Alexandre Patteet
École des Sciences criminelles (UNIL)



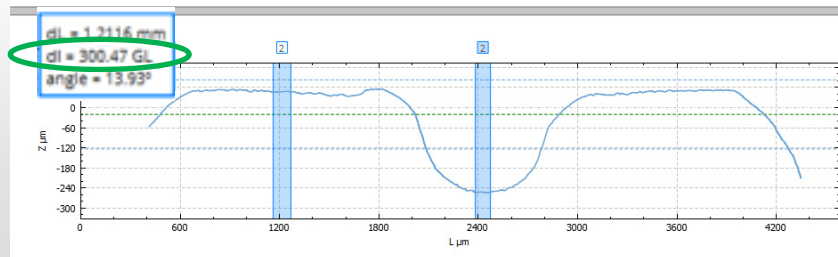
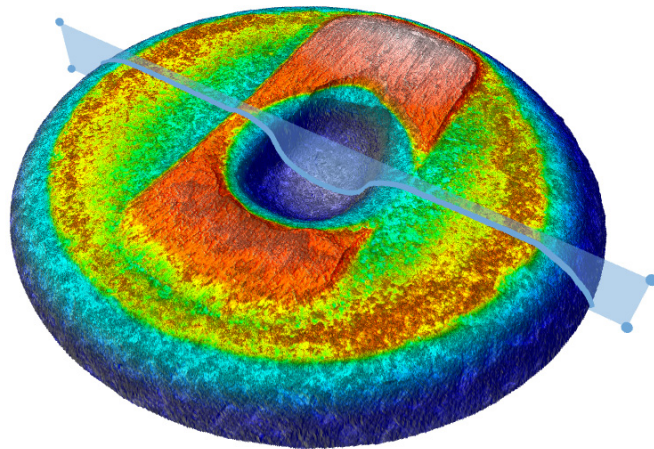
	Surface Rotation 0°	
	M1	M3
M2	0.289	0.917
M3	0.254	

	Surface Rotation 180°	
	M1	M3
M2	0.363	0.745
M3	0.378	

CRITICAL DIMENSIONS

CRITICAL DIMENSIONS

Firing pin impression depth measurements



Study by Luke Haag (Forensic Science Services)
3D2TWG (5th nov 2019)

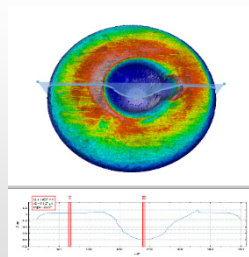
CRITICAL DIMENSIONS

Firing pin impression depth measurements

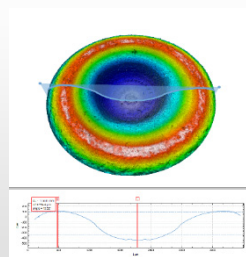
Cartridge ID	Firearm ID	Origen	Firearm	Ammunition	FP Depth Manual	FP Depth Auto	Dif	Dif %
SRM2461	SRM2461	NIST	-	-	619.3	621.9	-2.6	0%
C1	R1	Guardia Civil	Revolver .38 Special 1	Plomo desnudo	697.8	664.6	33.2	5%
C2	R1	Guardia Civil	Revolver .38 Special 1	Plomo desnudo	554.4	527.4	27.0	5%
C3	R1	Guardia Civil	Revolver .38 Special 1	Semiblandada	696.3	674.3	22.0	3%
C4	R1	Guardia Civil	Revolver .38 Special	Semiblandada	553.2	531.9	21.2	4%
C5	P1	Guardia Civil	Pistola	9 mm corto	617.7	576.4	41.3	7%
C6	P1	Guardia Civil	Pistola	9 mm corto	471.3	437.6	33.7	7%
C11	P3	Guardia Civil	Pistola TAURUS	9 mm Parabellum	511.1	487.6	23.6	5%
C12	P3	Guardia Civil	Pistola TAURUS	9 mm Parabellum	517.4	499.0	18.3	4%
C14	P4	ADFS	Pistol Beretta	9 mm	323.3	363.8	-40.4	-13%
C15	P4	ADFS	Pistol Beretta	9 mm	300.5	304.2	-3.7	-1%
A	P5	WVU	SCCY	9 mm luger	420.1	398.2	21.9	5%
B	P5	WVU	SCCY	9 mm luger	480.6	423.3	57.3	12%
C	P6	WVU	SCCY	9 mm luger	476.4	448.6	27.7	6%

Units: micrometers

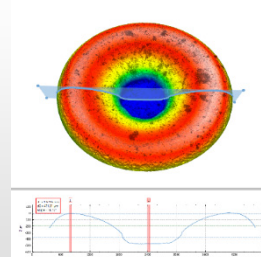
14 files / analysis time auto 120 s.



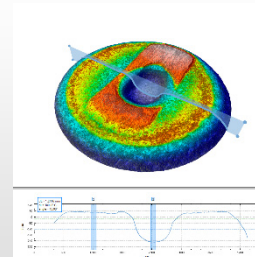
SRM2461



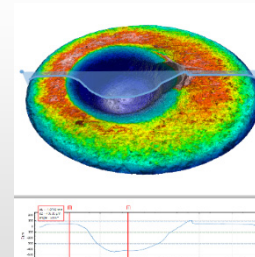
C3



C6



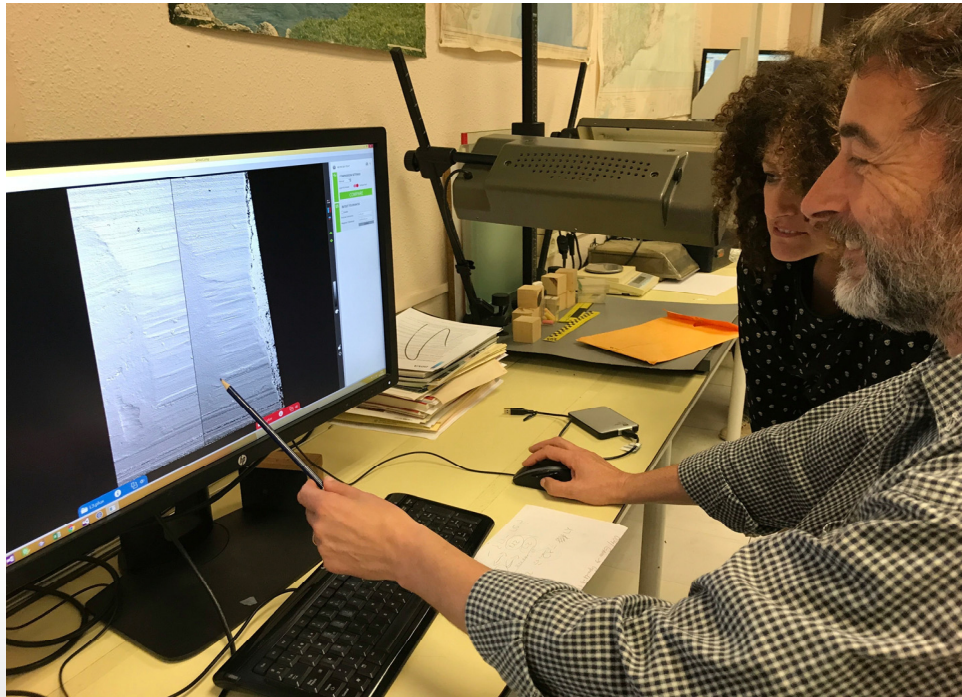
C15



C

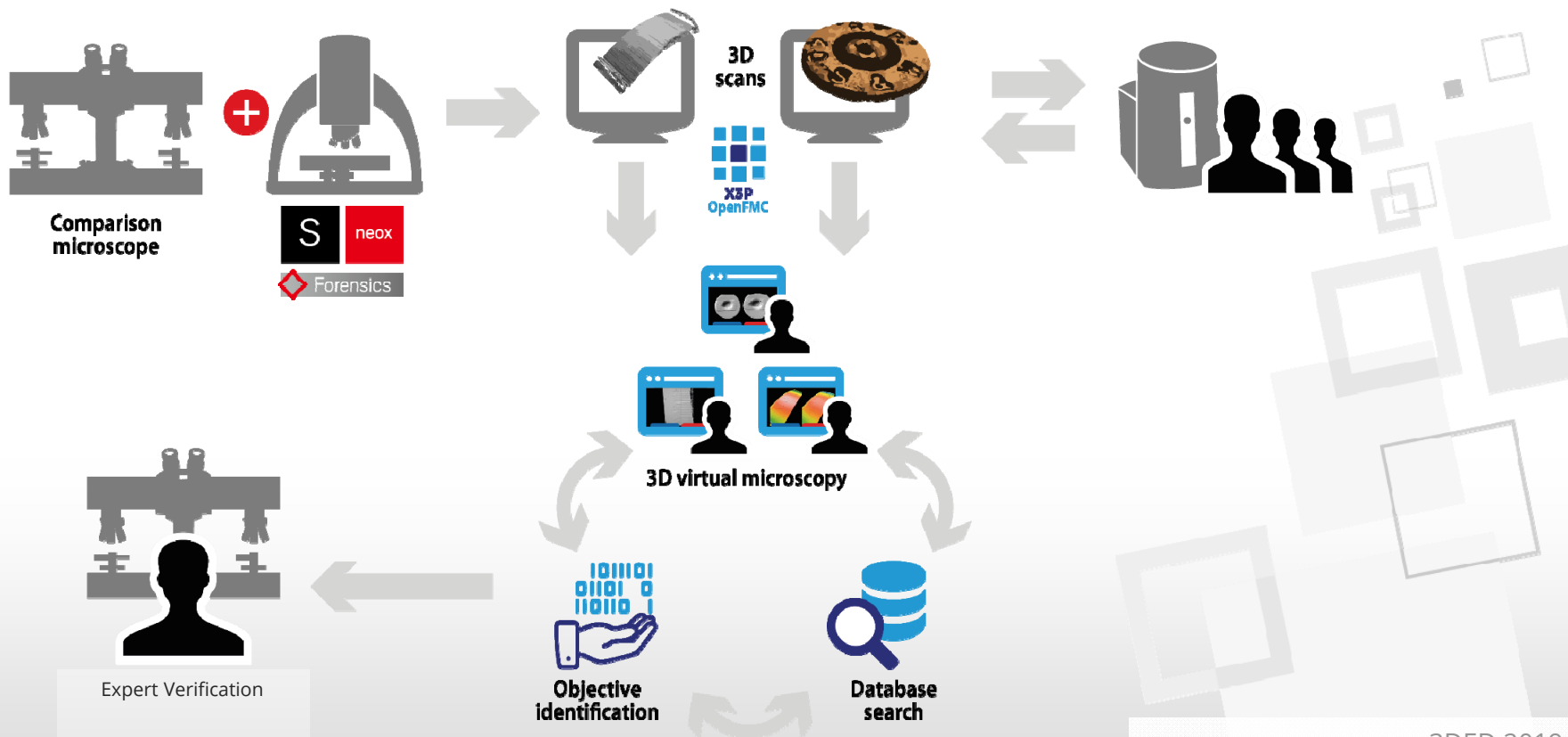
FUTURE

FUTURE



Antonio and Sara, examiners at Guardia Civil (Barcelona) using VCM SensoCOMP

FUTURE



Thank You!



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